

2020년 2월 13일(목), 10:45~12:30

Room C (사파이어 I, 5층)

H. Display and Imaging Technologies 분과
[TC2-H] Image Engineering & Sensors

TC2-H-1 10:45~11:15	[초청] Recent Technology Trends in Mobile Imaging Applications Jae-kyu Lee, Min-Woong Seo, Tae-Yon Lee, Myunglae Chu, Hyunchul Kim, JungChak Ahn, and Ho-kyu Kang <i>Semiconductor R&D Center, Samsung Electronics Co., Ltd.</i>
TC2-H-2 11:15~11:30	A Methodology for In-Fab Evaluation of Pinned Photodiode in CMOS Image Sensors Dongseok Cho, Sungin Kim, Jonghyun Go, Hyunchul Kim, Jaekyu Lee, and Jungchak Ahn <i>Semiconductor R&D Center, Samsung Electronics Co., Ltd.</i>
TC2-H-3 11:30~11:45	High-Sensitive And Transparent Strain Sensor Using Strain Engineered Substrate and Its Application For Human Motion Detection Inki Hwang, Daesik Kim, Geonhee Kim, and Yongtaek Hong <i>Department of Electrical and Computer Engineering and Inter-University Semiconductor Research Center (ISRC), Seoul National University</i>
TC2-H-4 11:45~12:00	Advanced Optical Collimator for Large Area OLED Fingerprint Sensor Ji Hun Ryu, Seung Hyun Moon, Chul Kim, Won Sang Park, and Bong-Hyun You <i>Samsung Display Co., Ltd</i>
TC2-H-5 12:00~12:15	2 Dimensional van der Waals Heterojunction Diode for Multiband Photo Detection Jongtae Ahn ^{1,2} , Hyun-soo Ra ¹ , and Do Kyung Hwang <i>¹Center for Opto-electronic Materials and Devices, Post-silicon Semiconductor Institute, KIST, ²Yonsei University</i>
TC2-H-6 12:15~12:30	Pressure-Sensitive Thin-Film Transistors Using Capacitance Modulation via Multiscale Surface Morphology of Embedded AgNWs Hayun Kim, Byeongmoon Lee, Hyunuk Oh, Hyunjun Yoo, Jaeyoung Yoon, and Yongtaek Hong <i>Department of Electrical and Computer Engineering and Inter-University Semiconductor Research Center (ISRC), Seoul National University</i>